

# Maximum Ratings N-CHANNEL – Q<sub>1</sub> (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Value	Unit
Drain Source Voltage	$V_{DSS}$	20	V
Gate-Source Voltage	V <sub>GSS</sub>	±8	V
Drain Current (Note 5) $T_A = +25^{\circ}C$ $T_A = +85^{\circ}C$	l ln	670 480	mA

# **Maximum Ratings P-CHANNEL – Q\_2** (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Value	Unit
Drain Source Voltage	$V_{DSS}$	-20	V
Gate-Source Voltage	$V_{GSS}$	±8	V
Drain Current (Note 5) $T_A = +25^{\circ}\text{C}$ $T_A = +85^{\circ}\text{C}$	ln ln	-530 -380	mA

### **Thermal Characteristics**

Characteristic	Symbol	Value	Units	
Total Power Dissipation (Note 5)		$P_{D}$	0.45	W
Thormal Posistance, Junction to Ambient (Note 5)	Steady state	6	281	°C/W
Thermal Resistance, Junction to Ambient (Note 5)	t<10s	$R_{\theta JA}$	210	°C/W
Total Power Dissipation (Note 6)		$P_{D}$	1	W
Thermal Resistance, Junction to Ambient (Note 6)	Steady state	C	129	°C/W
Thermal Resistance, Junction to Ambient (Note o)	t<10s	$R_{ heta JA}$	97	°C/W
Operating and Storage Temperature Range		$T_{J_1}T_{STG}$	-55 to +150	°C

### Electrical Characteristics N-CHANNEL - Q<sub>1</sub> (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 7)	OFF CHARACTERISTICS (Note 7)						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	20	_	_	V	$V_{GS} = 0V, I_D = 10\mu A$	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	_	_	1.0	μA	$V_{DS} = 16V, V_{GS} = 0V$	
Gate-Source Leakage	IGSS	_	_	± 1.0	μA	$V_{GS} = \pm 4.5 V, V_{DS} = 0 V$	
ON CHARACTERISTICS (Note 7)							
Gate Threshold Voltage	$V_{GS(th)}$	0.5	_	1.0	V	$V_{DS} = V_{GS}, I_D = 250 \mu A$	
		_	0.4	0.55		$V_{GS} = 4.5V, I_D = 540mA$	
Static Drain-Source On-Resistance	R <sub>DS (ON)</sub>	_	0.5	0.70	Ω	$V_{GS} = 2.5V, I_D = 500mA$	
		_	0.7	0.90		$V_{GS} = 1.8V, I_D = 350mA$	
Forward Transfer Admittance (Note 8)	Y <sub>fs</sub>	200	_		mS	$V_{DS} = 10V, I_D = 0.2A$	
Diode Forward Voltage	$V_{SD}$	0.5	_	1.2	V	$V_{GS} = 0V, I_{S} = 115mA$	
DYNAMIC CHARACTERISTICS							
Input Capacitance	C <sub>iss</sub>		_	150	pF		
Output Capacitance	Coss		_	25	pF	$V_{DS} = 16V, V_{GS} = 0V$ - f = 1.0MHz	
Reverse Transfer Capacitance	C <sub>rss</sub>	_	_	20	pF	T = T.OIVII IZ	

Device mounted on FR-4 substrate PC board, 2oz copper, with minimum recommended pad layout.
 Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.
 Short duration pulse test used to minimize self-heating effect.
 Guaranteed by design. Not subject to product testing.

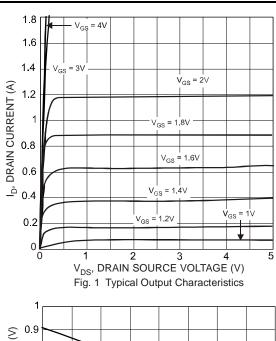


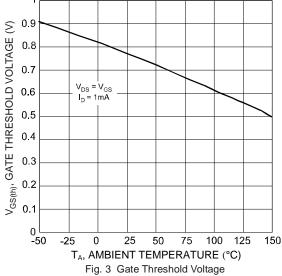
# Electrical Characteristics P-CHANNEL – Q<sub>2</sub> (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 7)	OFF CHARACTERISTICS (Note 7)					
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	-20	_	_	V	$V_{GS} = 0V, I_D = -250\mu A$
Zero Gate Voltage Drain Current	I <sub>DSS</sub>		_	-1.0	μA	$V_{DS} = -20V, V_{GS} = 0V$
Gate-Source Leakage	I <sub>GSS</sub>		_	± 1.0	μA	$V_{GS} = \pm 4.5V, V_{DS} = 0V$
ON CHARACTERISTICS (Note 7)						
Gate Threshold Voltage	V <sub>GS(th)</sub>	-0.5	_	-1.0	V	$V_{DS} = V_{GS}$ , $I_D = -250\mu A$
Static Drain-Source On-Resistance	R <sub>DS (ON)</sub>	_	0.7 1.1 1.7	0.9 1.4 2.0	Ω	$V_{GS} = -4.5V$ , $I_D = -430$ mA $V_{GS} = -2.5V$ , $I_D = -300$ mA $V_{GS} = -1.8V$ , $I_D = -150$ mA
Forward Transfer Admittance	Y <sub>fs</sub>	200	_	_	mS	$V_{DS} = 10V, I_D = 0.2A$
Diode Forward Voltage	V <sub>SD</sub>	-0.5	_	-1.2	V	$V_{GS} = 0V, I_{S} = -115mA$
DYNAMIC CHARACTERISTICS (Note 8)						
Input Capacitance	Ciss	_	_	175	pF	
Output Capacitance	Coss			30	pF	$V_{DS} = -16V, V_{GS} = 0V$ -f = 1.0MHz
Reverse Transfer Capacitance	C <sub>rss</sub>	_	_	20	pF	71 – 1.0101112



## Q<sub>1</sub>, N-CHANNEL





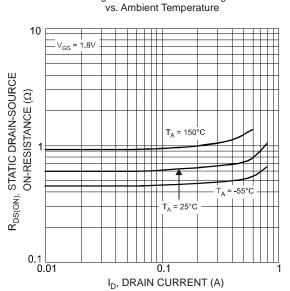
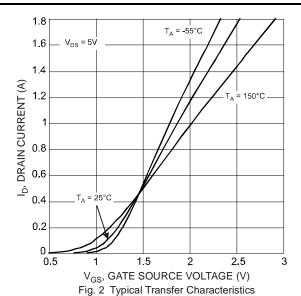


Fig. 5 Static Drain-Source On-Resistance vs. Drain Current



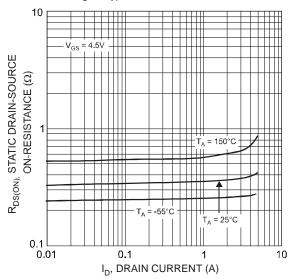


Fig. 4 Static Drain-Source On-Resistance vs. Drain Current

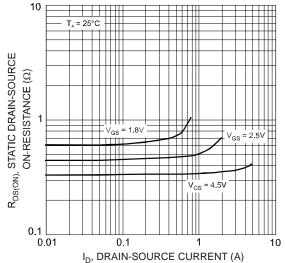


Fig. 6 Static Drain-Source On-Resistance vs. Drain-Source Current vs. Gate Source Voltage



### Q<sub>1</sub>, N-CHANNEL (cont.)

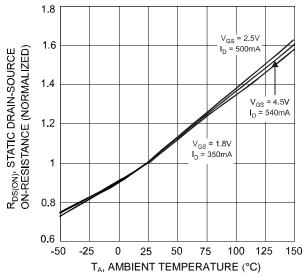


Fig. 7 Static Drain-Source On-State Resistance vs. Ambient Temperature

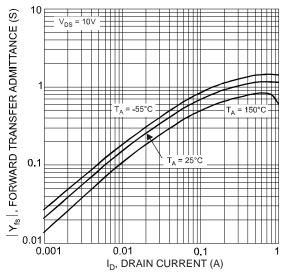


Fig. 9 Forward Transfer Admittance vs. Drain Current

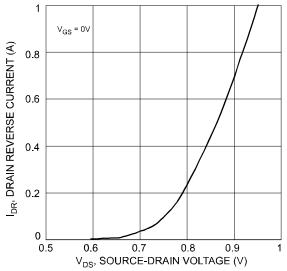
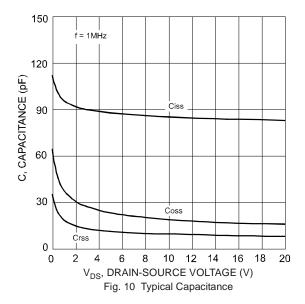
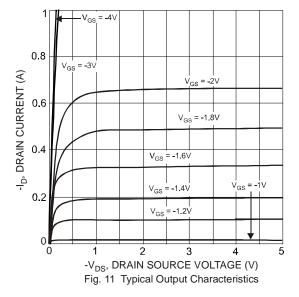


Fig. 8 Drain Reverse Current vs. Source-Drain Voltage





# Q<sub>2</sub>, P-CHANNEL



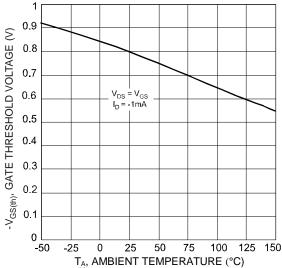


Fig. 13 Gate Threshold Voltage vs. Ambient Temperature

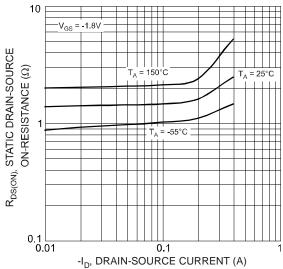
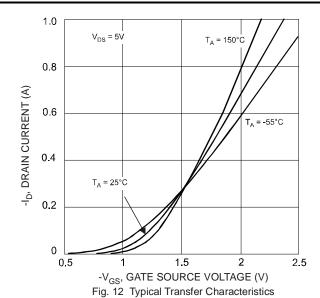


Fig. 15 Static Drain-Source On-Resistance vs.
Drain Current



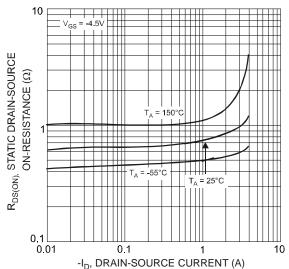


Fig. 14 Static Drain-Source On-Resistance vs. Drain Current

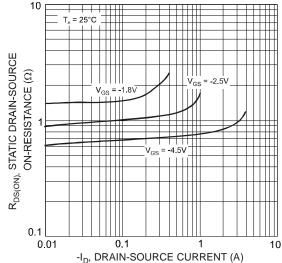


Fig. 16 Static Drain-Source On-Resistance vs. Drain-Source Current vs. Gate Source Voltage



#### Q<sub>2</sub>, P-CHANNEL (cont.)

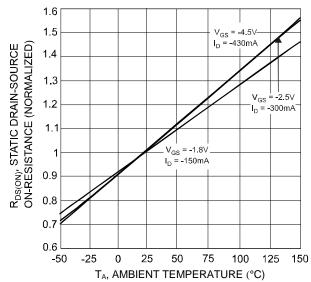


Fig. 17 Static Drain-Source On-State Resistance vs. Ambient Temperature

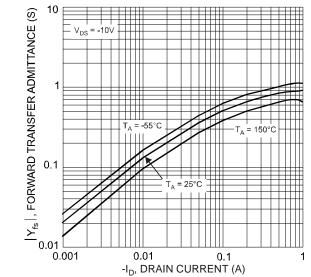


Fig. 19 Forward Transfer Admittance vs. Drain Current

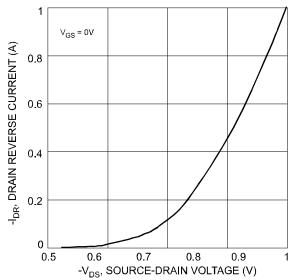
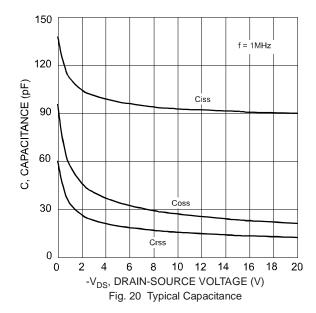


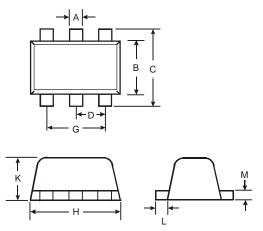
Fig. 18 Drain Reverse Current vs. Source-Drain Voltage





#### **Package Outline Dimensions**

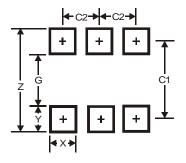
Please see http://www.diodes.com/package-outlines.html for the latest version.



SOT563					
Dim	Min	Max	Тур		
Α	0.15	0.30	0.20		
В	1.10	1.25	1.20		
С	1.55	1.70	1.60		
D	-	-	0.50		
G	0.90	1.10	1.00		
Н	1.50	1.70	1.60		
K	0.55	0.60	0.60		
L	0.10	0.30	0.20		
М	0.10	0.18	0.11		
All Dimensions in mm					

## **Suggested Pad Layout**

Please see http://www.diodes.com/package-outlines.html for the latest version.



Dimensions	Value (in mm)
Z	2.2
G	1.2
Х	0.375
Y	0.5
C1	1.7
C2	0.5



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